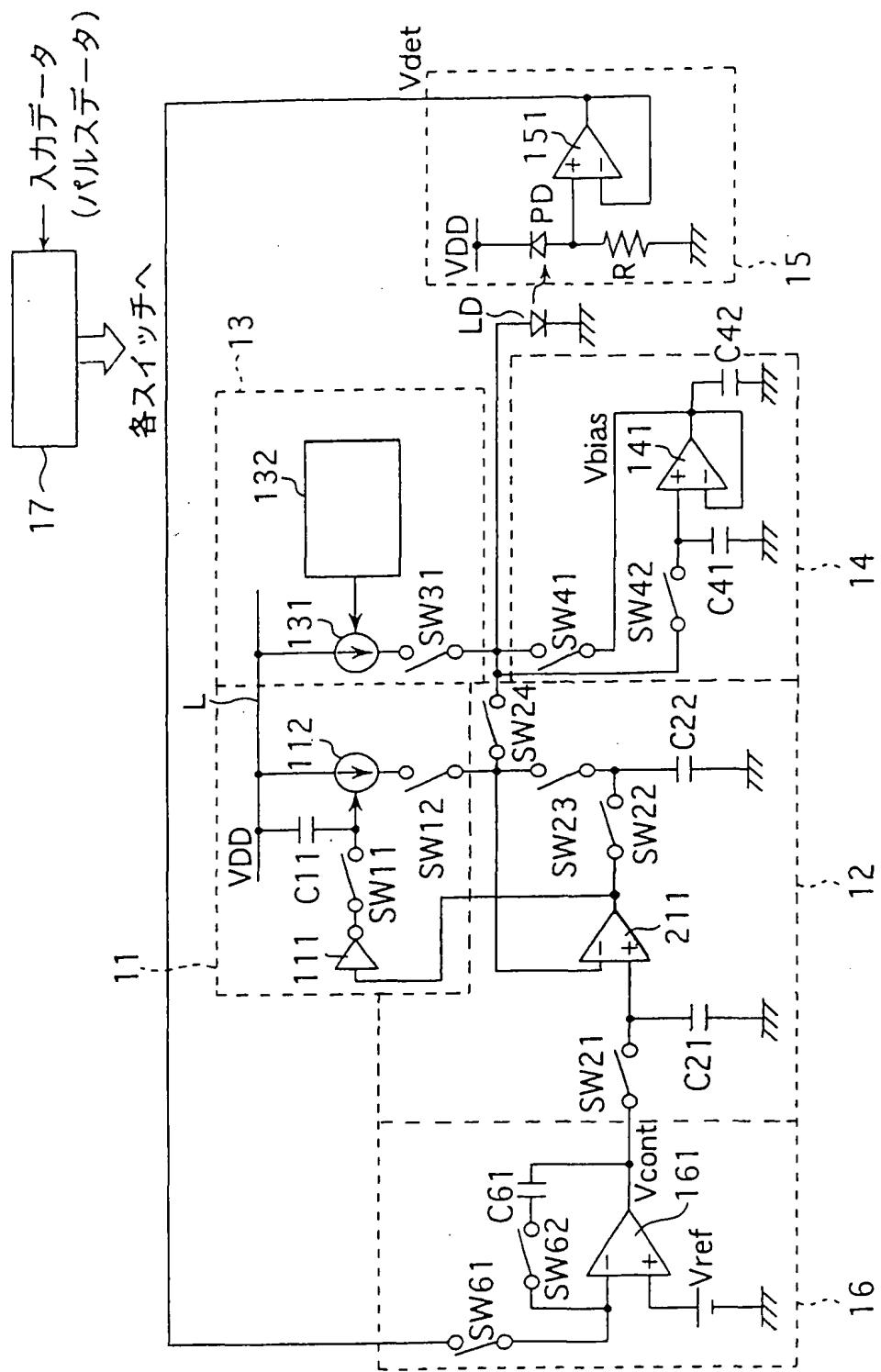


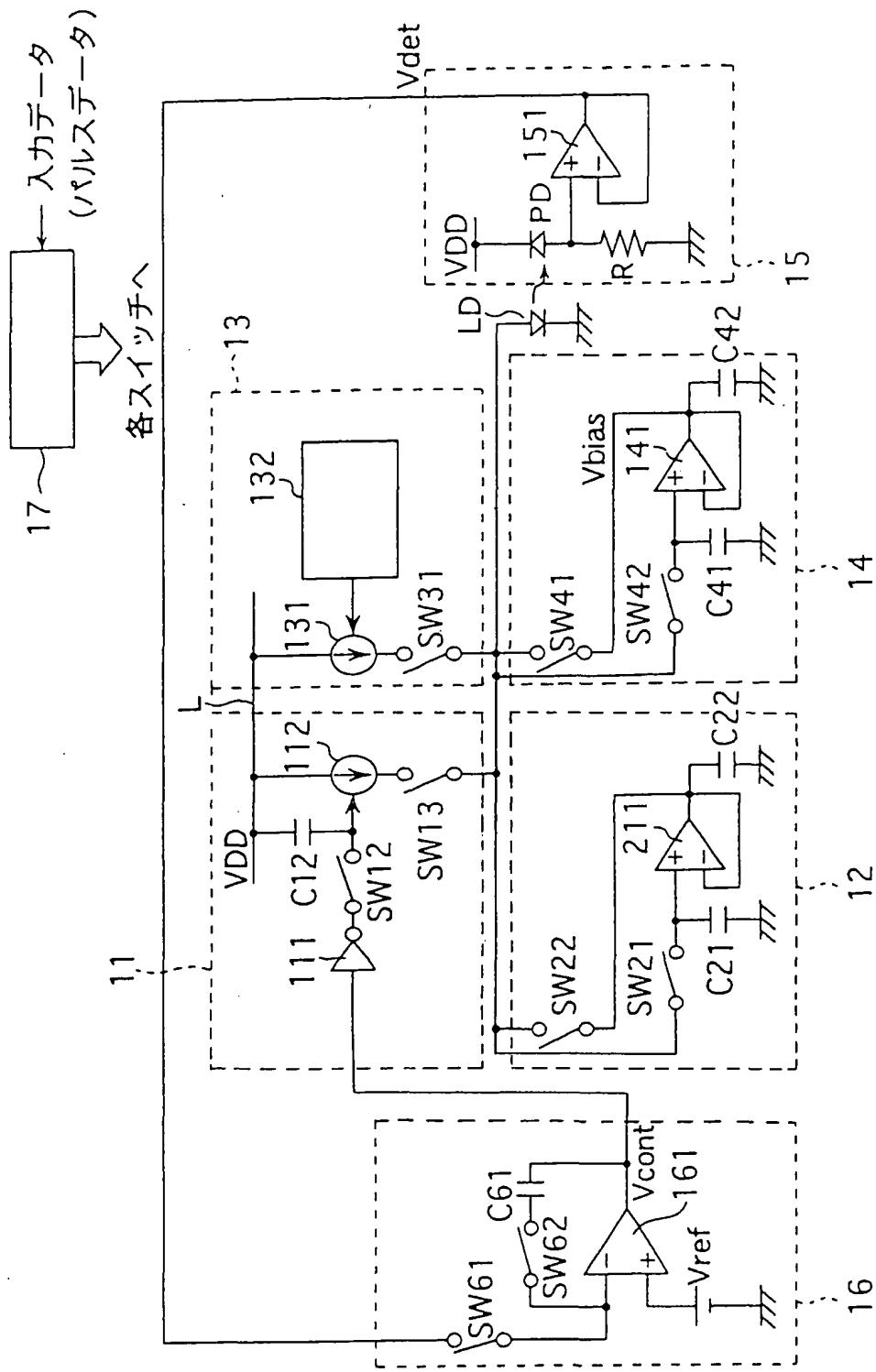
Fig. 1



[FIG. 1]

132: TEST CURRENT SETTING PORTION
 17: CONTROL CIRCUIT
 INPUT DATA (PULSE DATA)
 TO RESPECTIVE SWITCHES

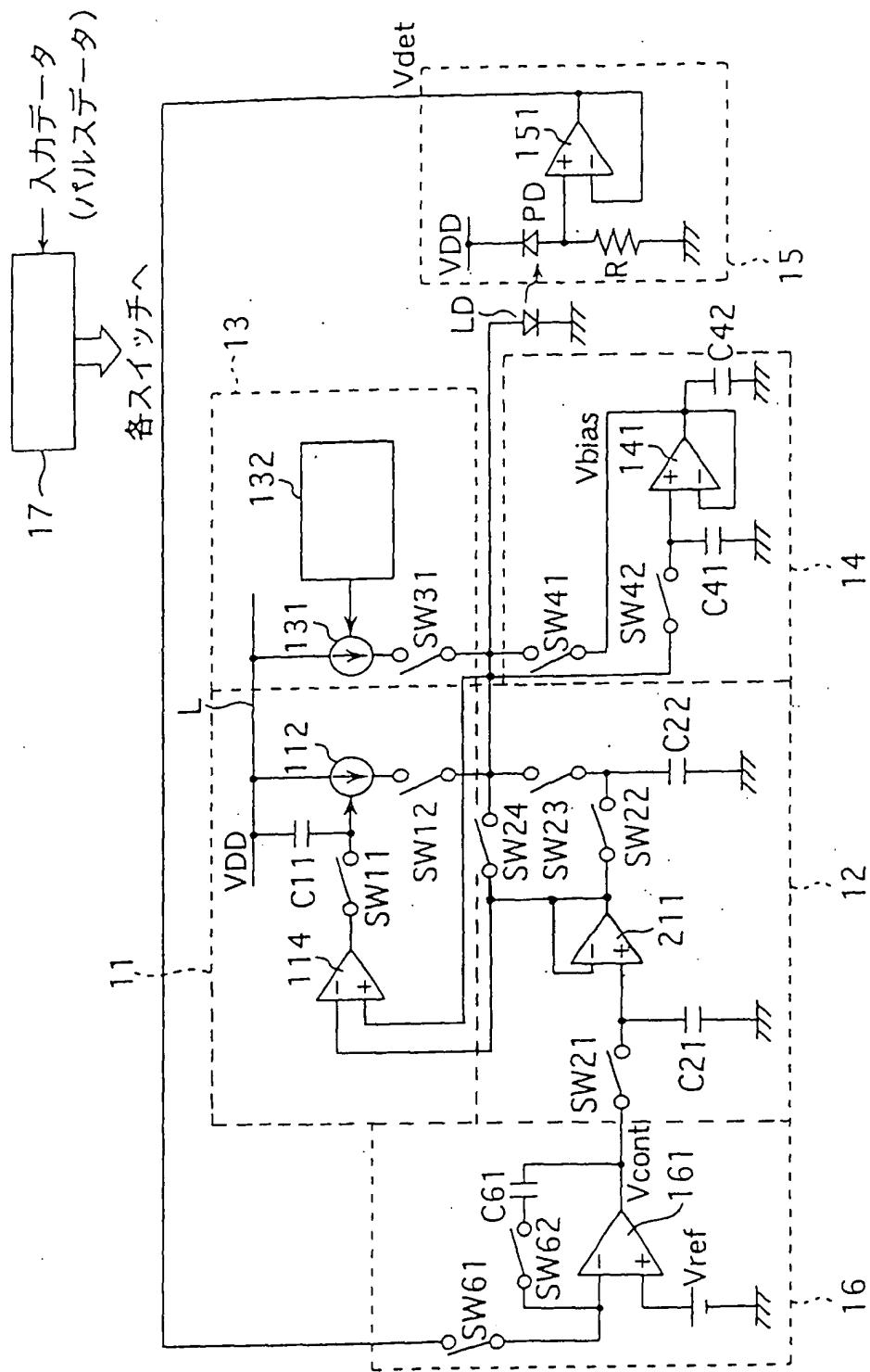
Fig. 2



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[FIG. 2] 132: TEST CURRENT SETTING PORTION
 17: CONTROL CIRCUIT
 INPUT DATA (PULSE DATA)
 TO RESPECTIVE SWITCHES

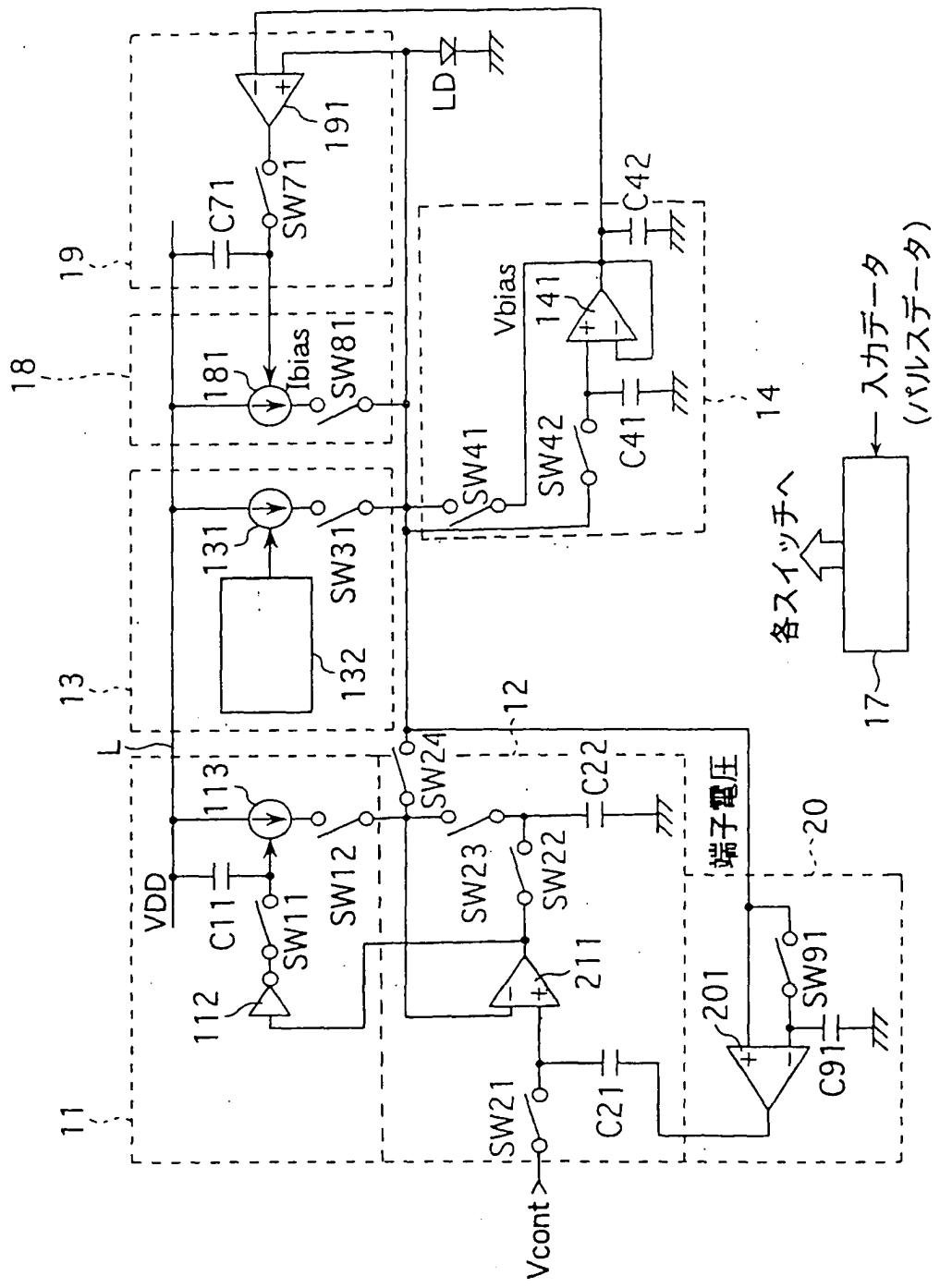
Fig. 3



[FIG. 3]

132: TEST CURRENT SETTING PORTION
 17: CONTROL CIRCUIT
 INPUT DATA (PULSE DATA)
 TO RESPECTIVE SWITCHES

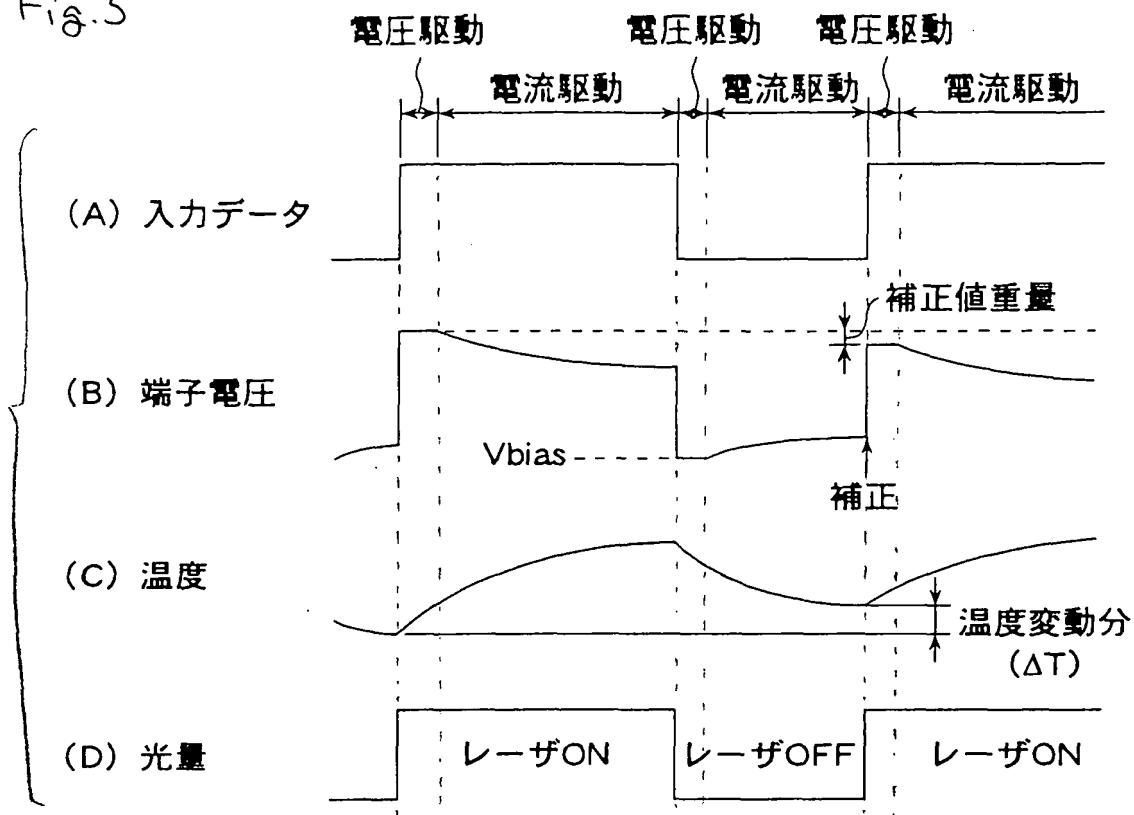
Fig. 4



[FIG. 4] 132: TEST CURRENT SETTING PORTION
 17: CONTROL CIRCUIT
 INPUT DATA (PULSE DATA)
 TO RESPECTIVE SWITCHES
 TERMINAL VOLTAGE

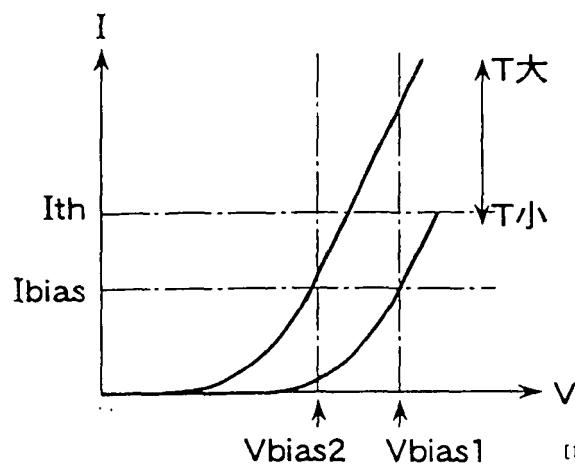
4
 10

Fig. 5



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Fig. 6



[FIG. 5]

A: INPUT DATA
 VOLTAGE DRIVE
 CURRENT DRIVE
 B: TERMINAL VOLTAGE
 CORRECTION VALUE SUPERPOSITION
 CORRECTION
 C: TEMPERATURE
 TEMPERATURE CHANGE (ΔT)
 D: LIGHT INTENSITY
 LASER ON
 LASER OFF

[FIG. 6]

T HIGH
 T LOW

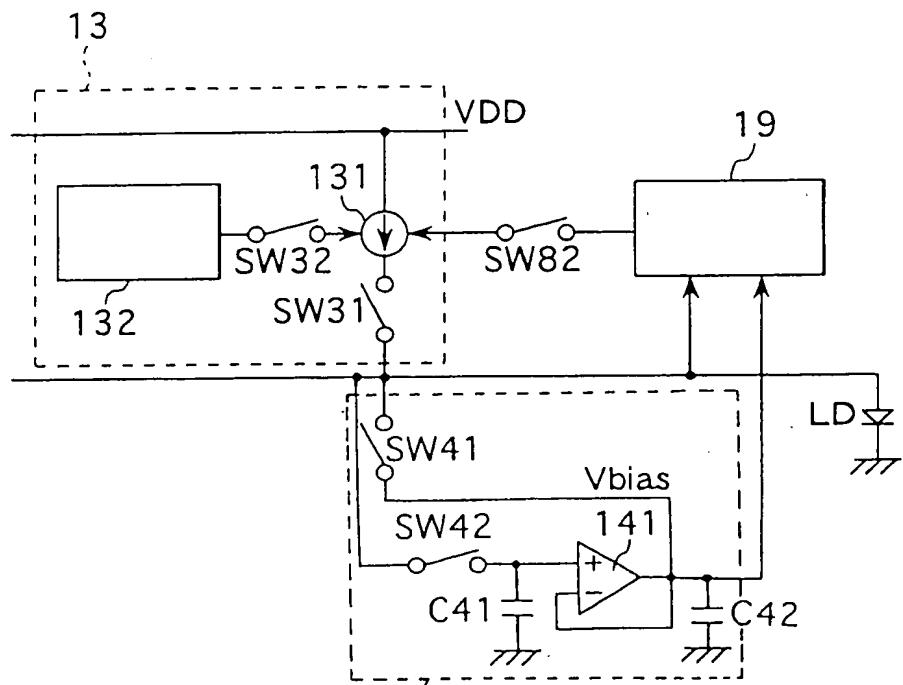


Fig. 7

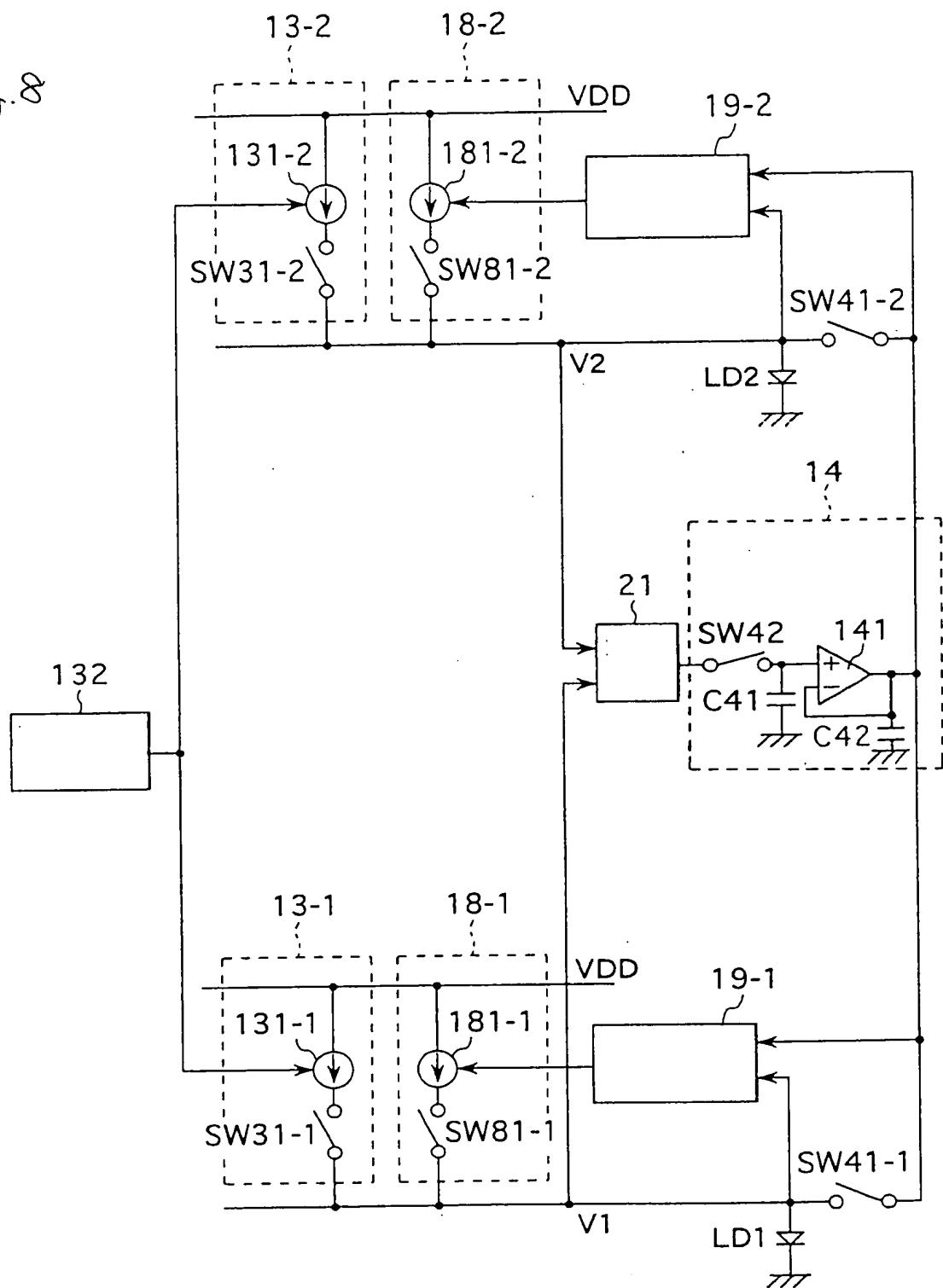
14.

[FIG. 7]

132: TEST CURRENT SETTING PORTION
19: BIAS CURRENT SETTING PORTION

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Fig. 8



[FIG. 8]

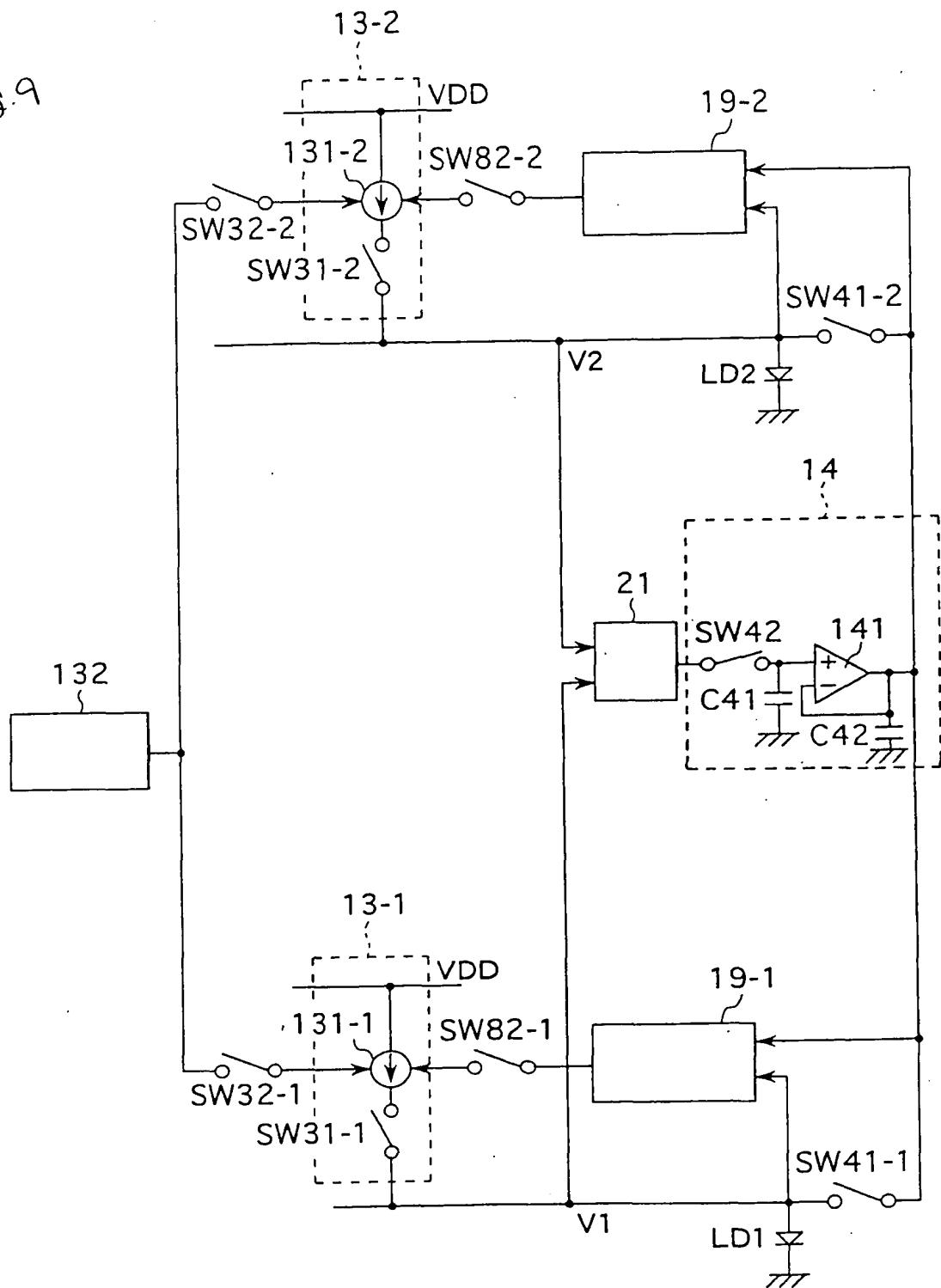
132: TEST CURRENT SETTING PORTION

19-1: BIAS CURRENT SETTING PORTION

19-2: BIAS CURRENT SETTING PORTION

21: ARITHMETIC CIRCUIT

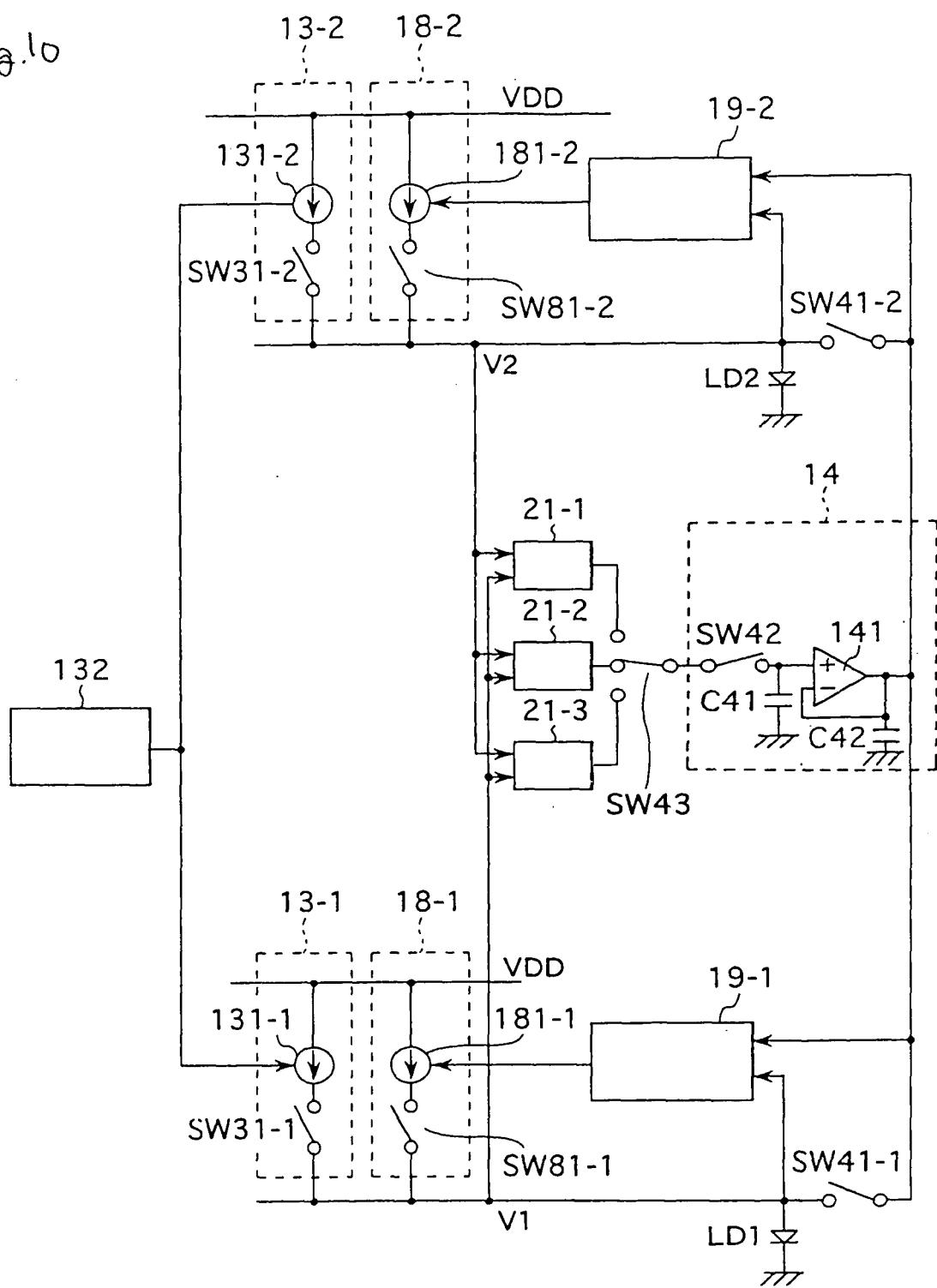
Fig. 9



[FIG. 9]

132: TEST CURRENT SETTING PORTION
19-1: BIAS CURRENT SETTING PORTION
19-2: BIAS CURRENT SETTING PORTION
21: ARITHMETIC CIRCUIT

Fig. 10



[FIG. 10]

132: TEST CURRENT SETTING PORTION

19-1: BIAS CURRENT SETTING PORTION

19-2: BIAS CURRENT SETTING PORTION

21-1: ARITHMETIC CIRCUIT

21-2: ARITHMETIC CIRCUIT

21-3: ARITHMETIC CIRCUIT

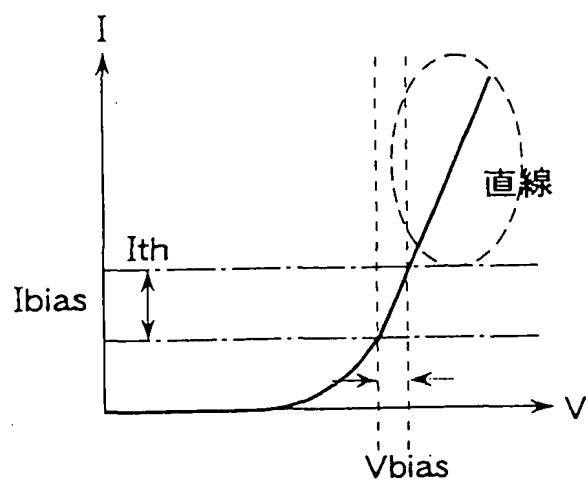


Fig. 11

[FIG. 11]
LINEAR